

# Silicon Tracking System Status

ILD Software & Integration Workshop 2010

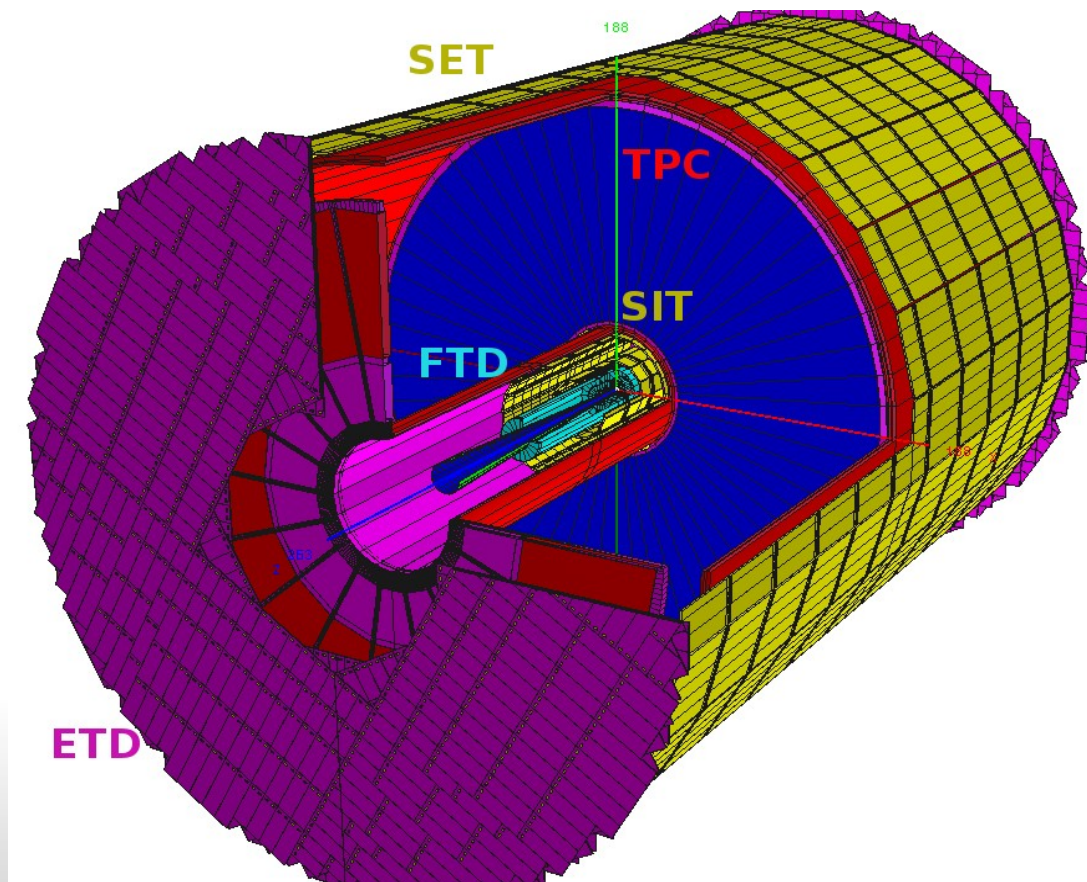
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Konstantin Androsov

# Full Geometry Description

Full description of the silicon tracker in the ILD concept

Goal:

- transition IlcRoot to Mokka with many improvements
- developing the mechanical structure according the workshop meeting ( ILD inner region integration meeting)
- SIT (HEPHY - INFN Turin - KEK - Korea – LPNHE)
- SET (INFN Turin - LPNHE)
- ETD (LPNHE)
- FTD (IFCA-IFIC)



# SiLC Framework

## Main Goals:

- Generate different kind of geometry very easily (number of silicon layers, false/true double-sided, technology ...) => automation
- Optimization of the geometry for physics studies (b-tagging, vertexing ... )
- Possibility to introduce mis-alignment studies according a mechanical structure
- Materiel budget effects induce by the support
- Customization for specific request (ILD ...)

## Inputs:

- XML configuration
- Mokka Database

# *SiLC Framework*

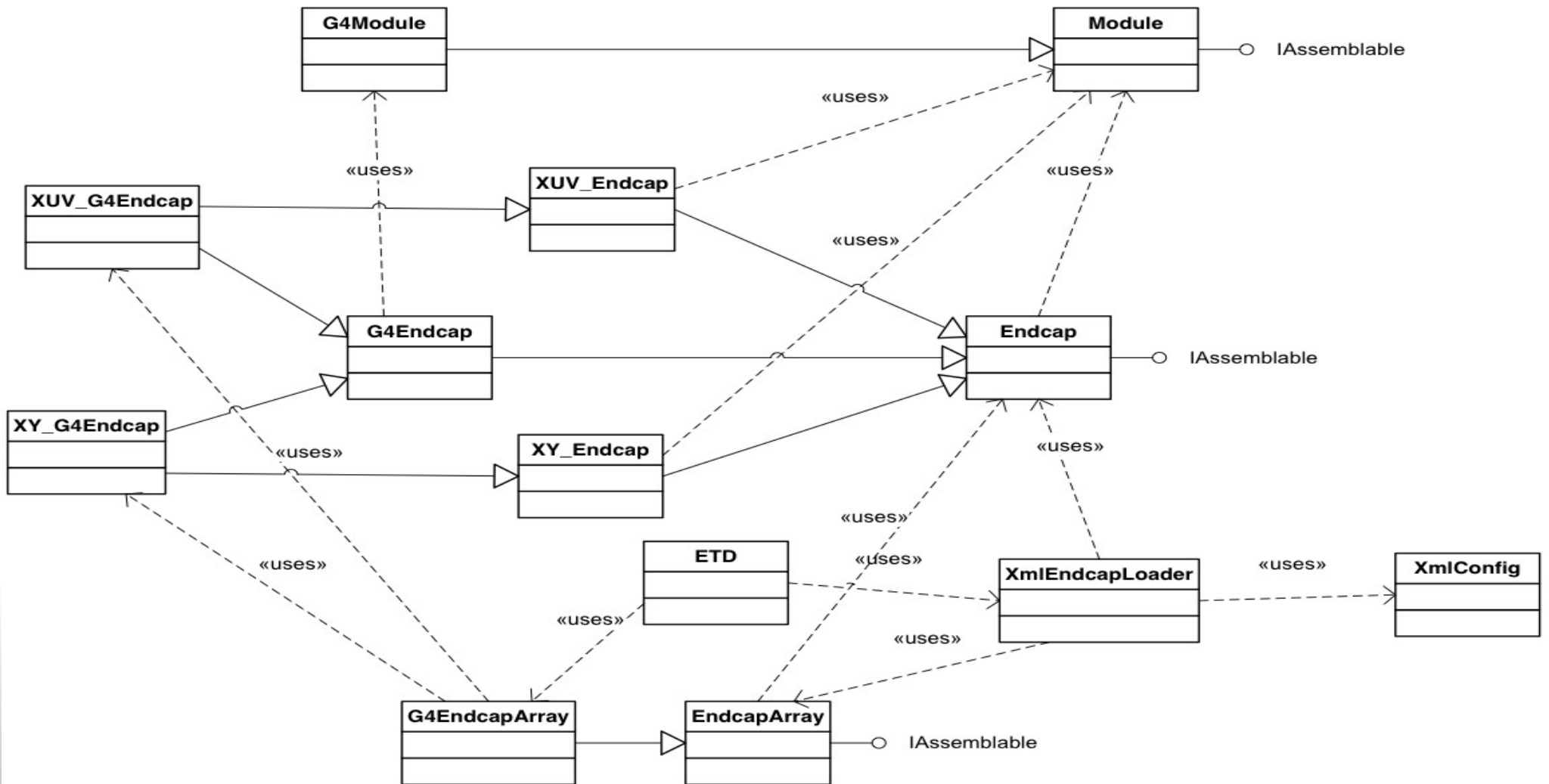
## Design concept

- Split the forward and the barrel region
- Both are created into several steps
  - build the silicon module
  - build the super-module
  - build the layer
  - build a detection element
  - build the sub-detectors

=> generic hierachy in the volume → misalignement studies ?
- Supports/cables builder could be disconnected to the active area builder
- Flexibility -> Interface to create dedicated geometry trough virtual methods

# SiLC Framework

## Partial design pattern

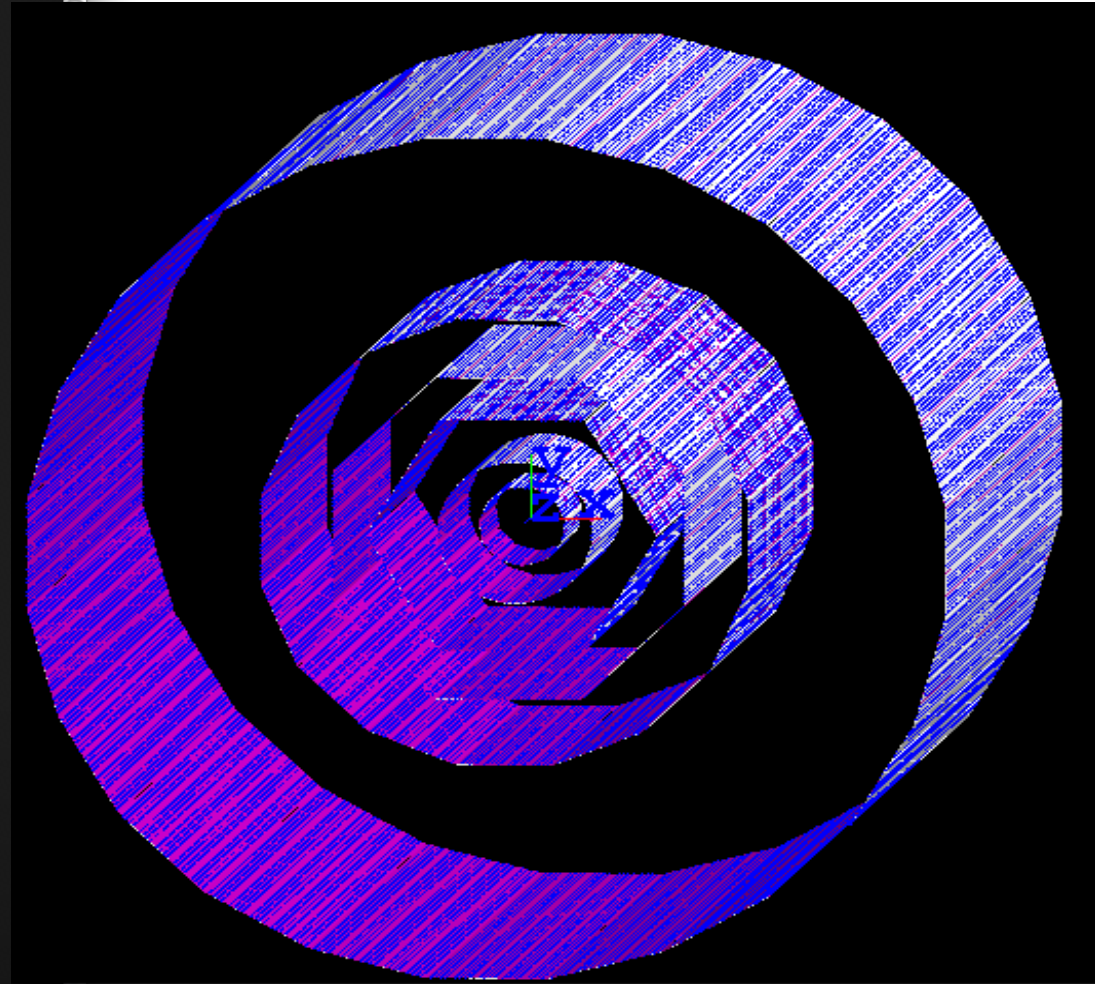


# SiLC Framework

## Example of application

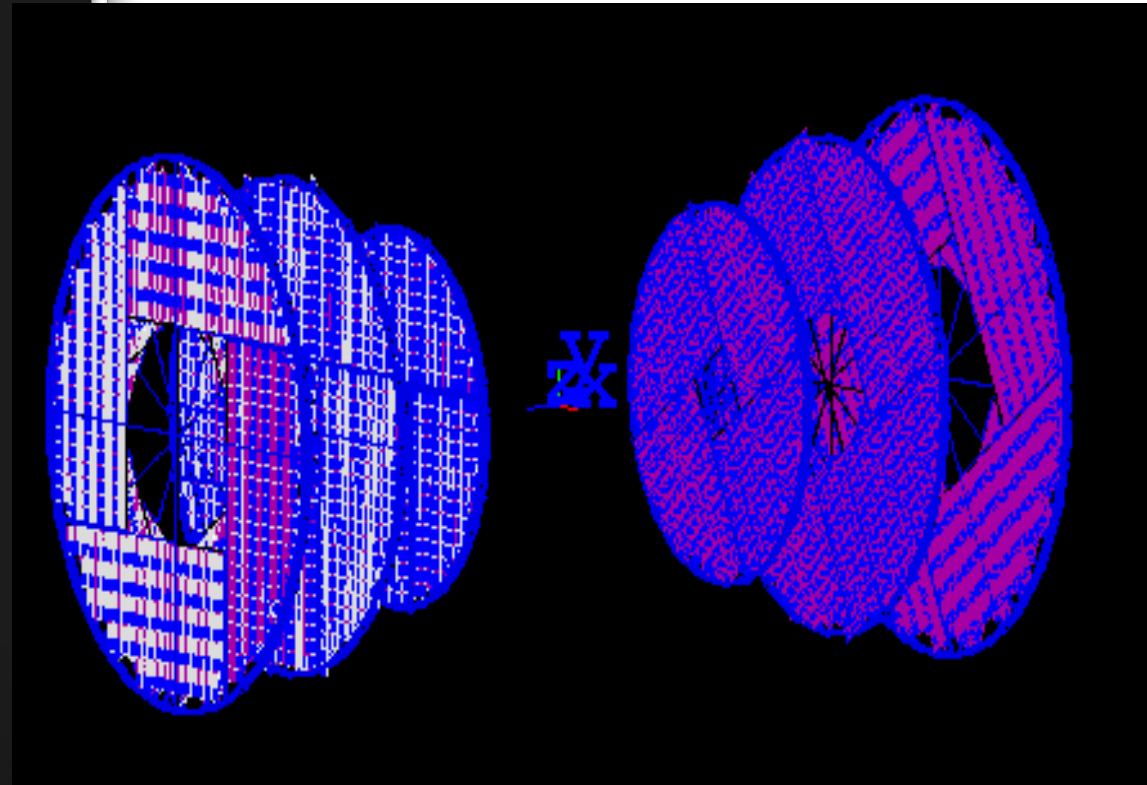
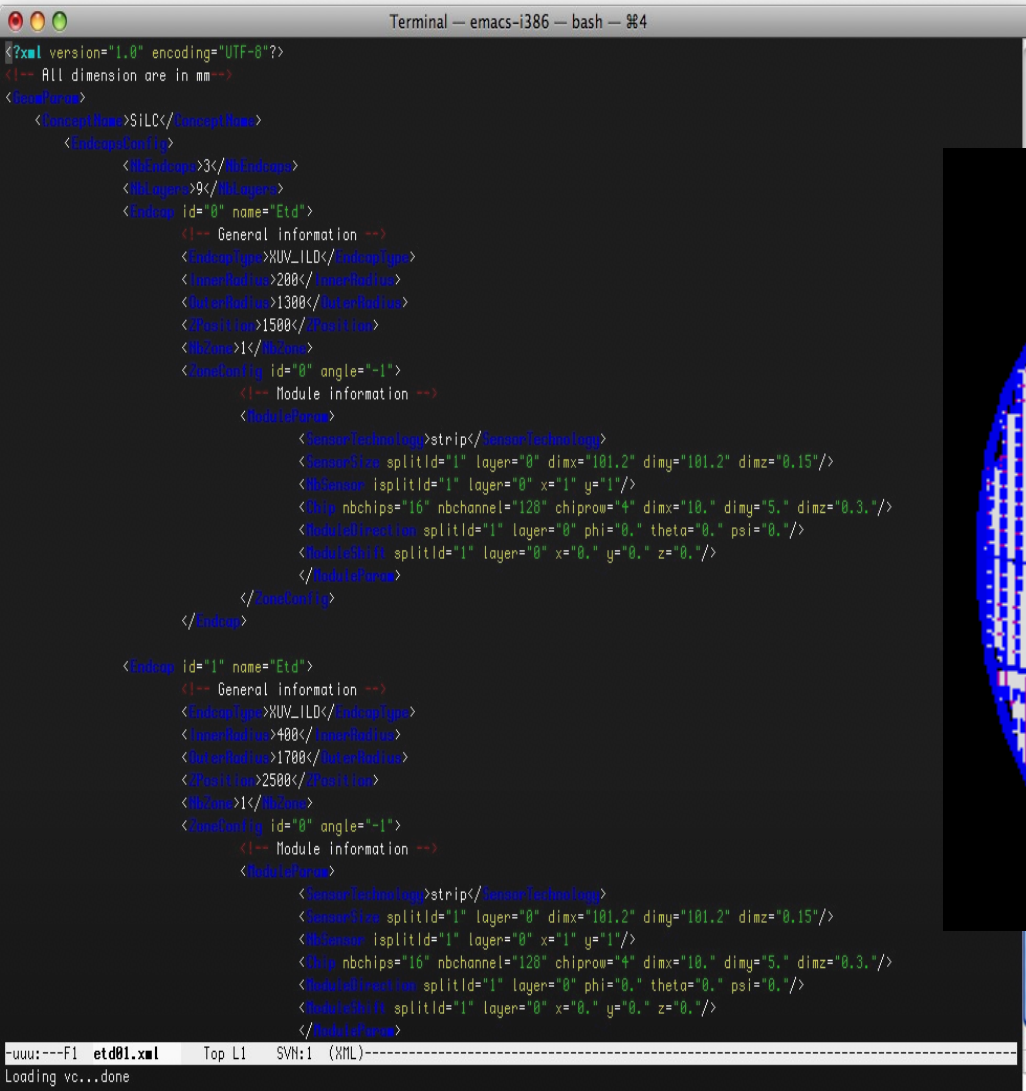
```
Terminal — emacs-i386 — bash — %4
<?xml version="1.0" encoding="UTF-8"?>
<!-- All dimension are in mm -->
<!-- General information -->
<!-- Module information -->
<!-- Chip Information -->
<!-- General information -->
<!-- Module information -->
<!-- Chip Information -->
```

uuuu:--F1 sit02.xml Top L1 SVN:7 (XML)-----  
Loading vc...done





## Example of application



# SiLC Framework for ILD concept

## Baseline:

- LOI

SIT characteristics (current baseline = false double-sided Si microstrips)					
Geometry			Characteristics		Material
R[mm]	Z[mm]	$\cos\theta$	Resolution R- $\phi[\mu\text{m}]$	Time [ns]	RL[%]
165	371	0.910	R: $\sigma=7.0$ , z: $\sigma=50.0$	307.7 (153.8) $\sigma=80.0$	0.65
309	645	0.902			0.65

SET characteristics (current baseline = false double-sided Si microstrips)					
Geometry			Characteristics		Material
R[mm]	Z[mm]	$\cos\theta$	Resolution R- $\phi[\mu\text{m}]$	Time [ns]	RL[%]
1833	2350	0.789	R: $\sigma=7.0$ , z: $\sigma=50.0$	307.7 (153.8) $\sigma=80.0$	0.65
1835	2350	0.789			0.65

- Silicon modules (will change according the results of next silicon tests)
  - sensors of 10.12\*10.12 mm<sup>2</sup>, edge-less technology
  - 2048 strip, 50 microns pitch, 200 microns of thickness
  - 16 SiTr read-out chips + one level concentrator + optical fiber output
  - power supply: kapton cable

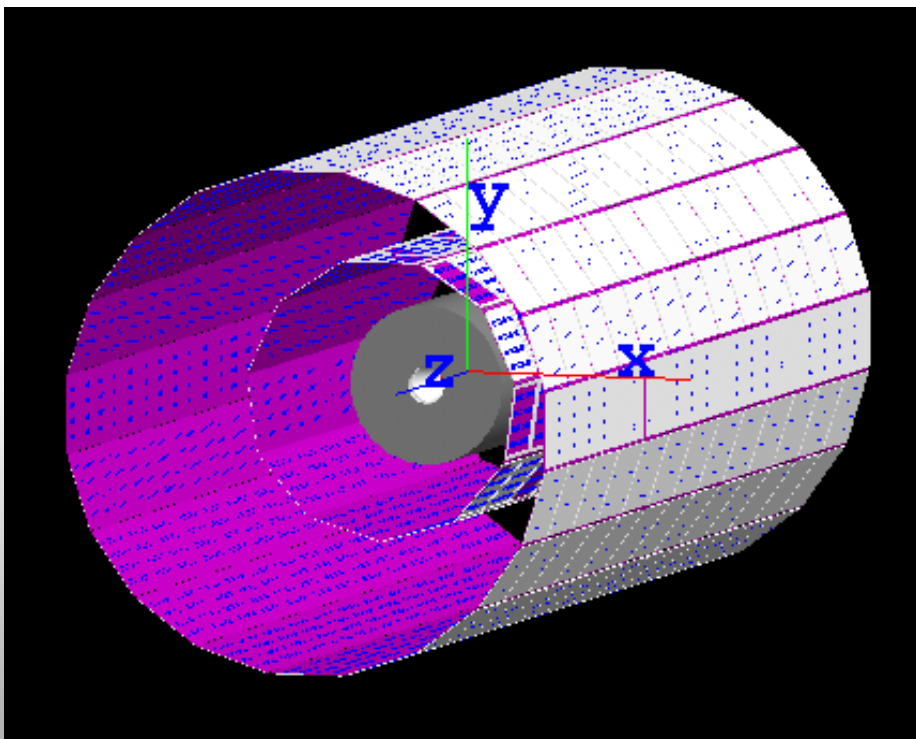


# Silicon Inner Tracker (SIT)

## LOI data

SIT characteristics (current baseline = false double-sided Si microstrips)					
Geometry			Characteristics		Material
R[mm]	Z[mm]	$\cos\theta$	Resolution R- $\phi$ [ $\mu\text{m}$ ]	Time [ns]	RL[%]
165	371	0.910	R: $\sigma=7.0$ , z: $\sigma=50.0$	307.7 (153.8) $\sigma=80.0$	0.65
309	645	0.902			0.65

## From Simulation



Simple layer with false double sided with  $6^\circ$  angle - Cf A.Savoy-Navarro

Minimum Radius (mm)	Maximum Radius (mm)	Z Length (mm)
172.3	179.6	708.4
319.5	323.5	1315.6

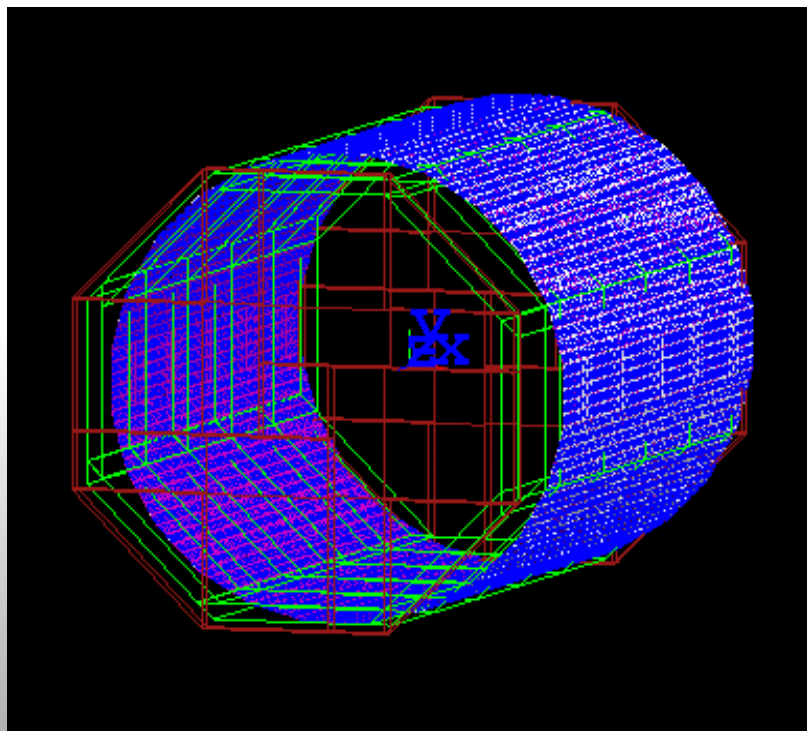
Number of modules along Z	Number of modules along $\phi$
7	11
13	20

# Silicon External Tracker (SET)

## LOI data

SET characteristics (current baseline = false double-sided Si microstrips)					
Geometry			Characteristics		Material
R[mm]	Z[mm]	$\cos\theta$	Resolution R- $\phi[\mu\text{m}]$	Time [ns]	RL[%]
1833	2350	0.789	R: $\sigma=7.0$ , z: $\sigma=50.0$	307.7 (153.8) $\sigma=80.0$	0.65
1835	2350	0.789			0.65

## From Simulation



Simple layer with false double sided with  $6^\circ$  angle - Cf A.Savoy-Navarro

Number Of Super Module	Number of modules along Z	Number of modules along $\phi$
24	48	120

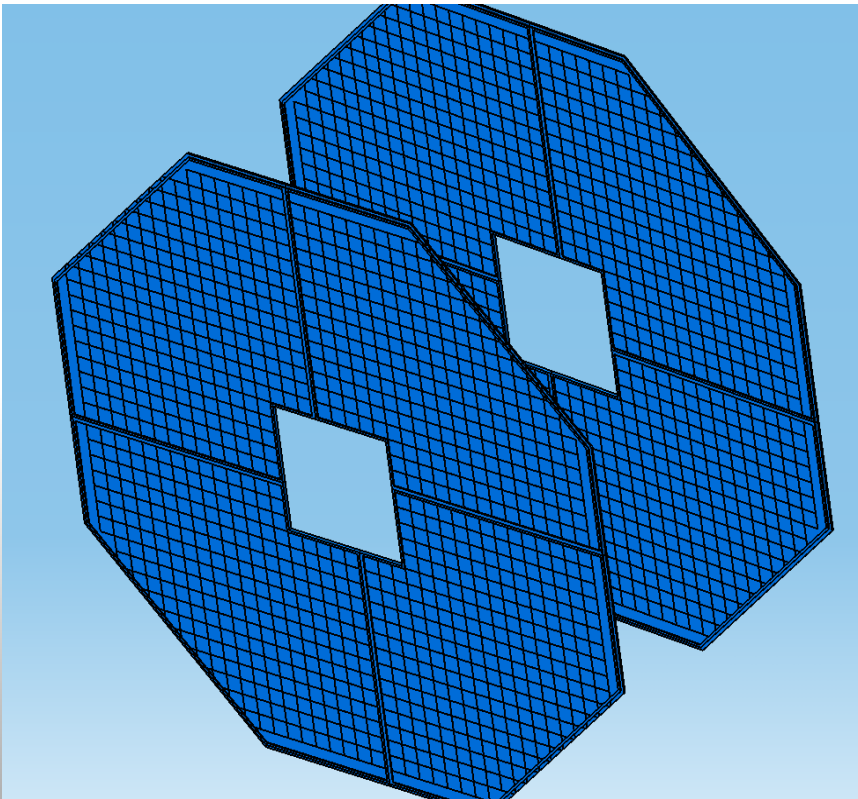
Minimum Radius (mm)	Maximum Radius (mm)	Z Length (mm)
1921 mm	1938 mm	4857 mm

Support under mechanical studies

# Endcap Tracking Detector (ETD)

## LOI data

ETD characteristics (current baseline = single-sided Si micro-strips, same as SET ones)				
Geometry			Characteristics	Material
R[mm]	Z[mm]	$\cos\theta$	Resolution R- $\phi[\mu\text{m}]$	RL[%]
419.3-1822.7	2426	0.985-0.799	x: $\sigma=7.0$	0.65
419.3-1822.7	2428	0.985-0.799	y: $\sigma=7.0$	0.65
419.3-1822.7	2430	0.985-0.799	z: $\sigma=7.0$	0.65



Multiple ETD versions:

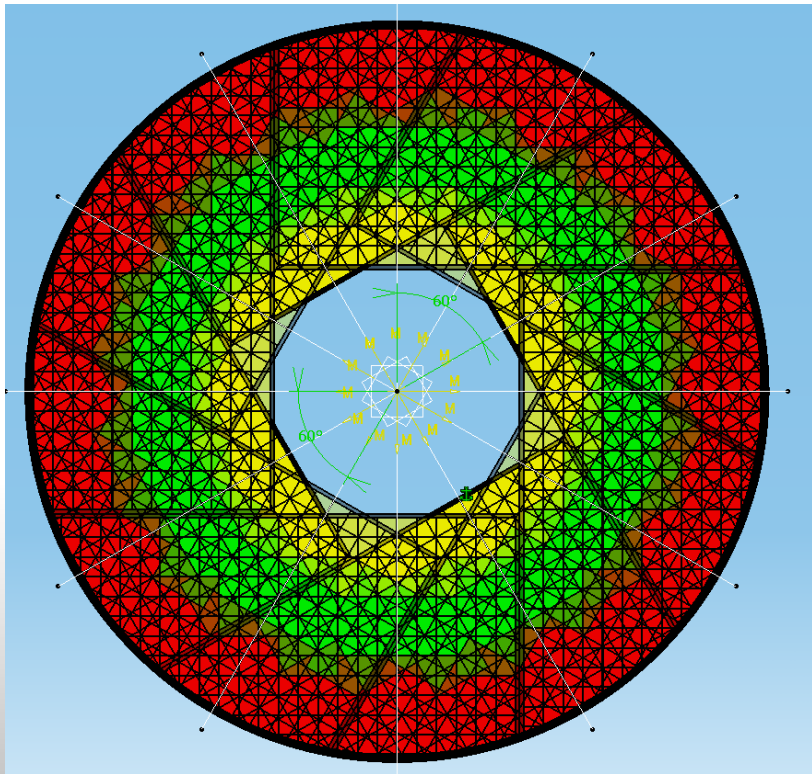
- XUV version
- one layer of double sided sensors with stereo-angle
- and one more

-> the limits are strictly fixed by the ECAL endcaps  
=> need to evaluate the surface of non active area, make many adjustments and study effect on the reconstruction

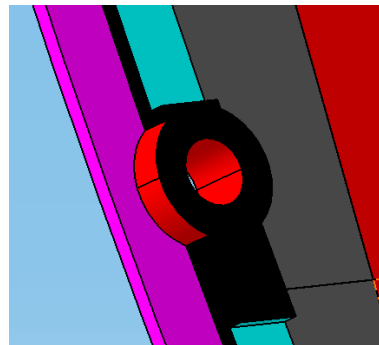
# Endcap Tracking Detector (ETD)

## XUV concept

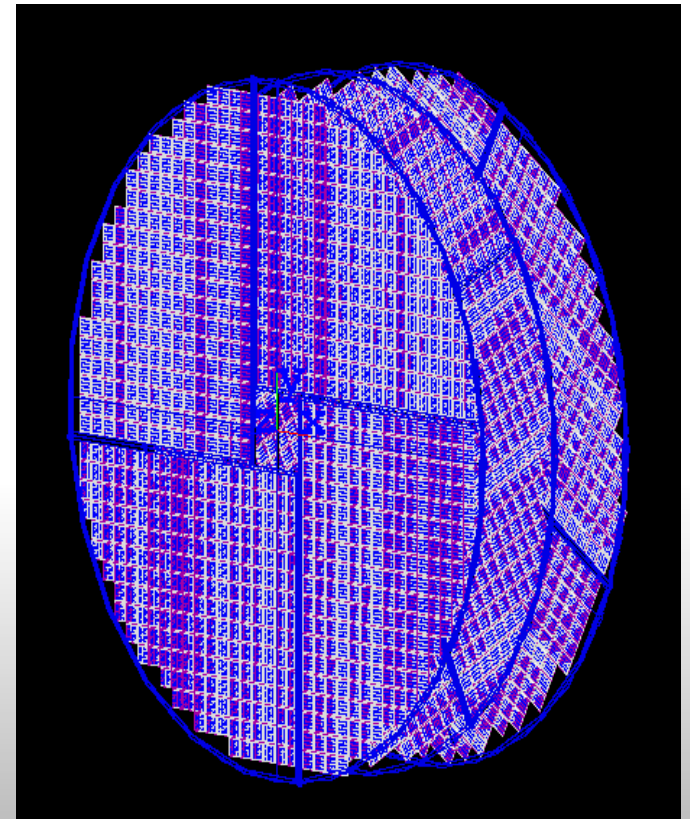
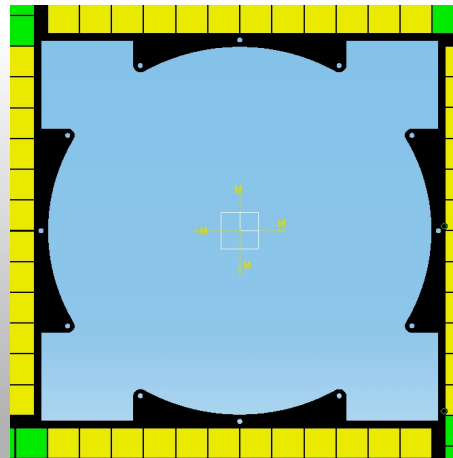
- pixels is required at forward rapidity
- Small details have to be completed



CATIA



to



GEANT 4

# Silicon Tracking System Status

## Overview

# TODO list

- Check the overlapping for different configurations and fix the exceptions
- Creation and link with the Mokka database (thanks to Paulo Mora de Freitas)
- Manual writing (important)
- Complete the mechanical structure and the cable path according the dedicated engineers
- Commit of the source code under a SiLC directory

## Expected End of July

- For reconstruction: what is required ?
- Link with the digitization



# Thanks for your attention